Applicant(s)/Patent Under Application/Control No. Reexamination 10/743,595 VAN KAMPEN ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 Juvena W. Loo 2609 **U.S. PATENT DOCUMENTS** Document Number Date Name Classification Country Code-Number-Kind Code MM-YYYY US-2005/0018624 A1 01-2005 Meier et al. 370/318 Α US-2005/0138451 A1 06-2005 Simpson et al. 713/320 В С US-D US-US-Ε US-F US-G US-Н US-US-J US-Κ US-L US-М FOREIGN PATENT DOCUMENTS **Document Number** Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν 0 Р Q R s Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U

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